Advanced Small Signal MOSFET

FEATURES

- Lower R_{DS(on)}
- Improved Inductive Ruggedness
- Fast Switching Times
- □ Lower Input Capacitance
- D Extended Safe Operating Area
- □ Improved High Temperature Reliability

Product Summary

Part Number	\mathbf{BV}_{DSS}	R _{DS} (on)	I _D
2N7002	2N7002 60V		115mA

Absolute Maximum Ratings

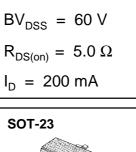
Symbol	Characteristic	Value	Units	
V _{DSS}	Drain-to-Source Voltage	60	V	
	Continuous Drain Current (T _c =25°C)	115	mA	
I_D Continuous Drain Current ($T_C=100^{\circ}C$)		73	mA	
I _{DM}	Drain Current-Pulsed (1)	800	mA	
V _{GS}	Gate-to-Source Voltage	±20	V	
_	Total Power Dissipation (T _C =25°C)	0.2	W	
P _D	Linear Derating Factor	0.16	W/℃	
	Operating Junction and		°C	
T_J , T_STG	Storage Temperature Range	- 55 to +150	C	

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{\Theta JA}$	Junction-to-Ambient		62.5	°C/W



2N7002MTF





2N7002MTF

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition	
BV _{DSS}	Drain-Source Breakdown Voltage	60	-	-	V	$V_{GS} = 0V, I_{D} = 250 \mu A$	
V _{GS(th)}	Gate Threshold Voltage	1.2	-	2.5	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
	Gate-Source Leakage, Forward	-	-	100	m A	V _{GS} = 20V	
I _{GSS}	Gate-Source Leakage, Reverse	-	-	-100	nA	V _{GS} = -20V	
	Drain to Course Lookana Current	-	-	1.0	μA	$V_{GS} = 40V$	
I _{DSS}	Drain-to-Source Leakage Current	-	-	500	μη	V _{GS} = 40V, T _C = 125℃	
I _{D(ON)}	On-State Drain-Source Current	0.5	-	-	А	$V_{DS} = 10V, V_{GS} = 10V$	
D	Static Drain-Source			- 5.0	Ω	V _{GS} = 10V, I _D = 0.5A	
R _{DS(on)}	On-State Resistance (2)	-		5.0	52	$V_{\rm GS} = 100, I_{\rm D} = 0.3 A$	
g _{fs}	Forward Transconductance ②	0.08	-	-	S	$V_{DS} = 15V, I_{D} = 0.2A$	
C _{iss}	Input Capacitance	-	-	50			
C _{oss}	Output Capacitance	-	-	25	pF	$V_{DS} = 25V, V_{GS} = 0V,$ f = 1.0MHz	
C _{rss}	Reverse Transfer Capacitance	-	-	5			
t _{d(on)}	Turn-On Delay Time	-	-	20			
t _r	Rise Time	-	-	-	$V_{DD} = 30V, I_D = 0.2A$		
t _{d(off)}	Turn-Off Delay Time	-	-	20	ns	$R_{G} = 25\Omega$ (2)(3)	
t _f	Fall Time	-	-	-			

Electrical Characteristics (T_C=25 $^\circ C$ unless otherwise specified)

Source-Drain Diode Ratings and Characteristics

Symbol	Symbol Characteristic		Тур.	Max.	Units	Test Condition	
۱ _s	Continuous Source Current		-	115	mA	Integral reverse pn-diode	
I _{SD}	Pulse Source Current ①	-	-	800	mA	In the MOSFET	
V _{SD}	Diode Forward Voltage ②	-	-	1.5	V	T _A = 25 ℃, I _S = 115mA V _{GS} = 0V	

Notes;

① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature

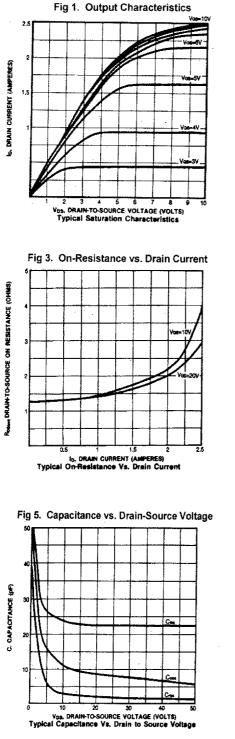
2 Pulse Test : Pulse Width = 250µs, Duty Cycle \leq 2%

③ Essentially Independent of Operating Temperature



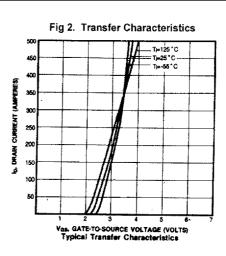
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2N7002MTF

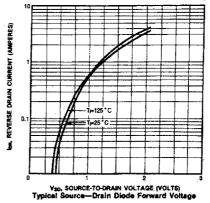




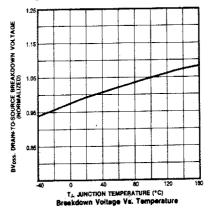
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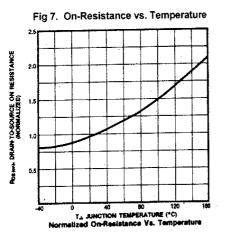














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Programmable Ac	tive Droop™	OPTOPLANAR™	SMART START™	

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